TUZ 2027

Call for Papers



Hamburg, February 21.-23., 2027

39. ITG / GMM / GI - Workshop Testmethoden und Zuverlässigkeit von Schaltungen und Systemen

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ABOUT

The workshop “Test Methods and Reliability of Circuits and Systems” is the most important German forum for discussing trends, results and current problems in the field of testing, diagnostics and reliability of digital, analog, mixed signal and RF circuits. The world-wide exchange of ideas is an important concern of the workshop. International contributions from both industrial practice and research institutions are welcome. We welcome highly practice related experience reports and results as well as contributions on theoretical topics from the following areas, among others:

- hardware-oriented test and hardware-oriented security
- fault tolerance, resilience, robust and radiation-hard systems
- dependability and functional safety
- adaptive systems (e.g. self-repair, self-healing, self-awareness)
- statistical and AI-learning for test and reliability
- automatic test-equipment, test automation, test programs and test modeling
- defect- and fault models
- diagnosis of failure causes
- test and simulation of mixed-Signal, HF- and analog-circuit-test
- test generation, fault simulation, self-test and online-test
- test-oriented design, DfT methods
- test costs and quality
- test standards, e.g IEEE 1149.x, IEEE 1687.x, IEEE 1838

PARTICIPATION

The workshop will take place in the beautiful city of Hamburg and is organized by the TUHH. The event is planned to be held entirely in person. Interested parties are asked to submit a summary of their contribution of a maximum of two pages in 2 column IEEE-format via the workshop homepage. The contribution should describe the purpose of the work, the novelty and aspects of the application. Accepted contributions will be included in the informal workshop handout upon request. The contribution can be extended to four pages for this purpose.

IMPORTANT DATES & SUBMISSION

Submission of Title & Abstract:	~~November 1st 2026~~ November 8th 2026
Submission of Full Paper:	~~November 9th 2026~~ November 15th 2026
Author Notification:	December 22nd 2026
Camera-ready Paper:	January 18th 2027
Submission-Page:	https://easychair.org/conferences/?conf=tuz2027
Webpage:	www.tuz2027.rp.es.tuhh.de

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